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# Chapter 1

## Introduction to The Semiconductor Industry

# The Semiconductor Industry

## INFRASTRUCTURE

Industry Standards  
(SIA, SEMI, NIST, etc.)

Production Tools

Utilities

Materials & Chemicals

Metrology Tools

Analytical Laboratories

Technical Work Force

Colleges & Universities

**Chip  
Manufacturer**

## PRODUCT APPLICATIONS

Consumers:

- Computers
- Automotive
- Aerospace
- Medical
- other industries

Customer Service

Original Equipment Manufacturers

Printed Circuit Board Industry

**Worldwide sales of microchips : > \$250 billion in 2005**

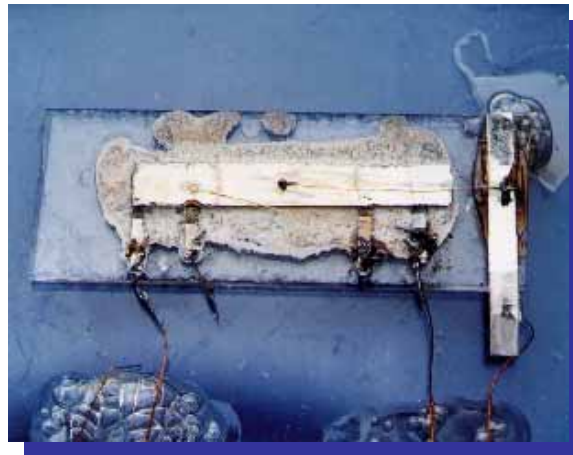
# From Devices to Integrated Circuits

**(1947) The First Solid-state Transistor**



Lucent Technologies, **Bell Labs** Innovations, William Shockley, John Bardeen, Walter Brattain (1956 Nobel Prize in physics)

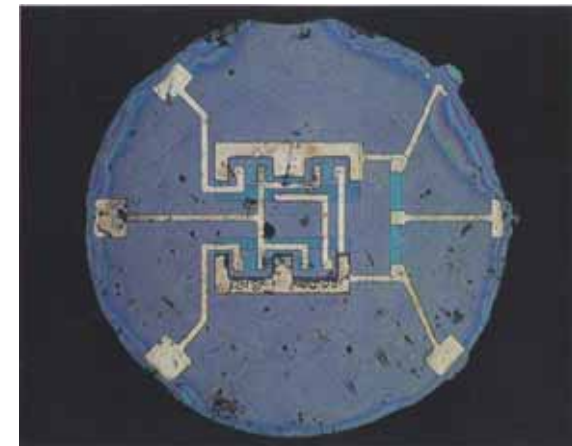
**(1958) The First Integrated Circuit (IC) Device - Oscillator IC ( 5 components )**



**Texas Instruments**, Inc., Jack Kilby

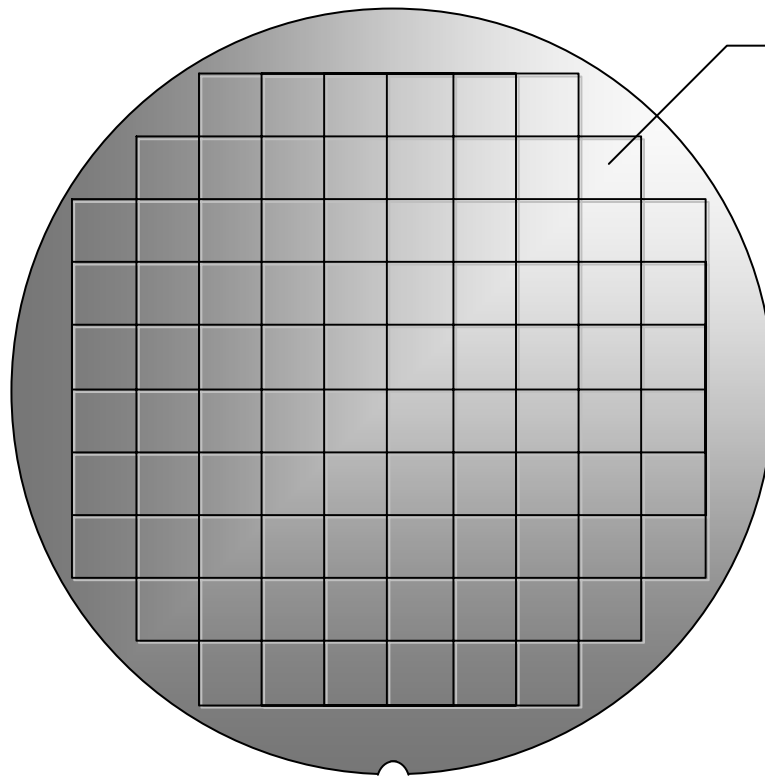
- 1950s: Transistor Technology
- 1960s: Process Technology
- 1970s: Competition
- 1980s: Automation
- 1990s: Volume Production

**(1961) The First Planar IC (Transistor+R+C)**



**Fairchild Semiconductor**, California (Silicon Valley), Robert Noyce

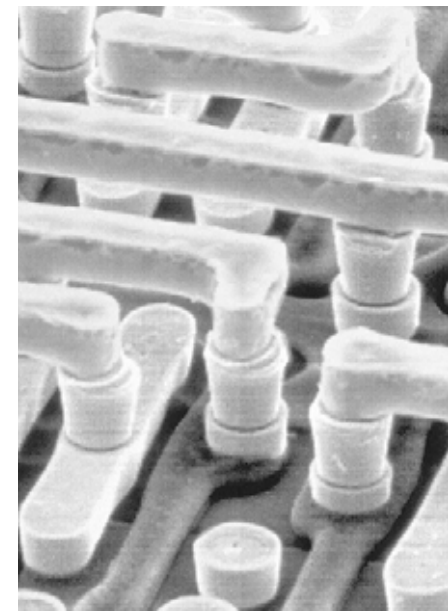
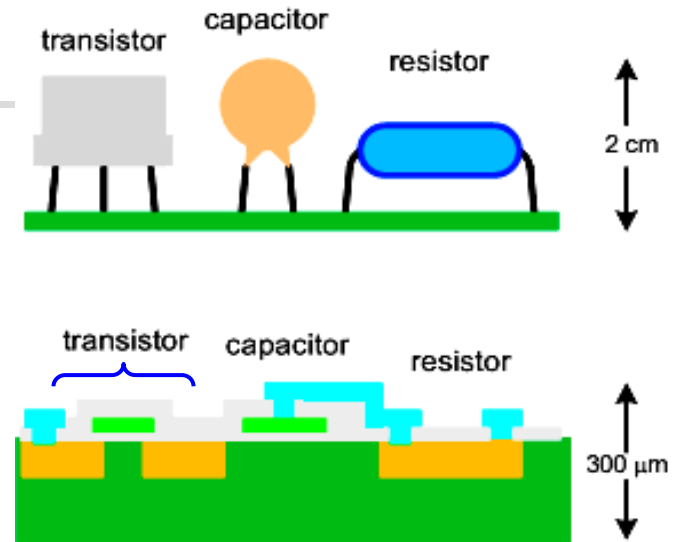
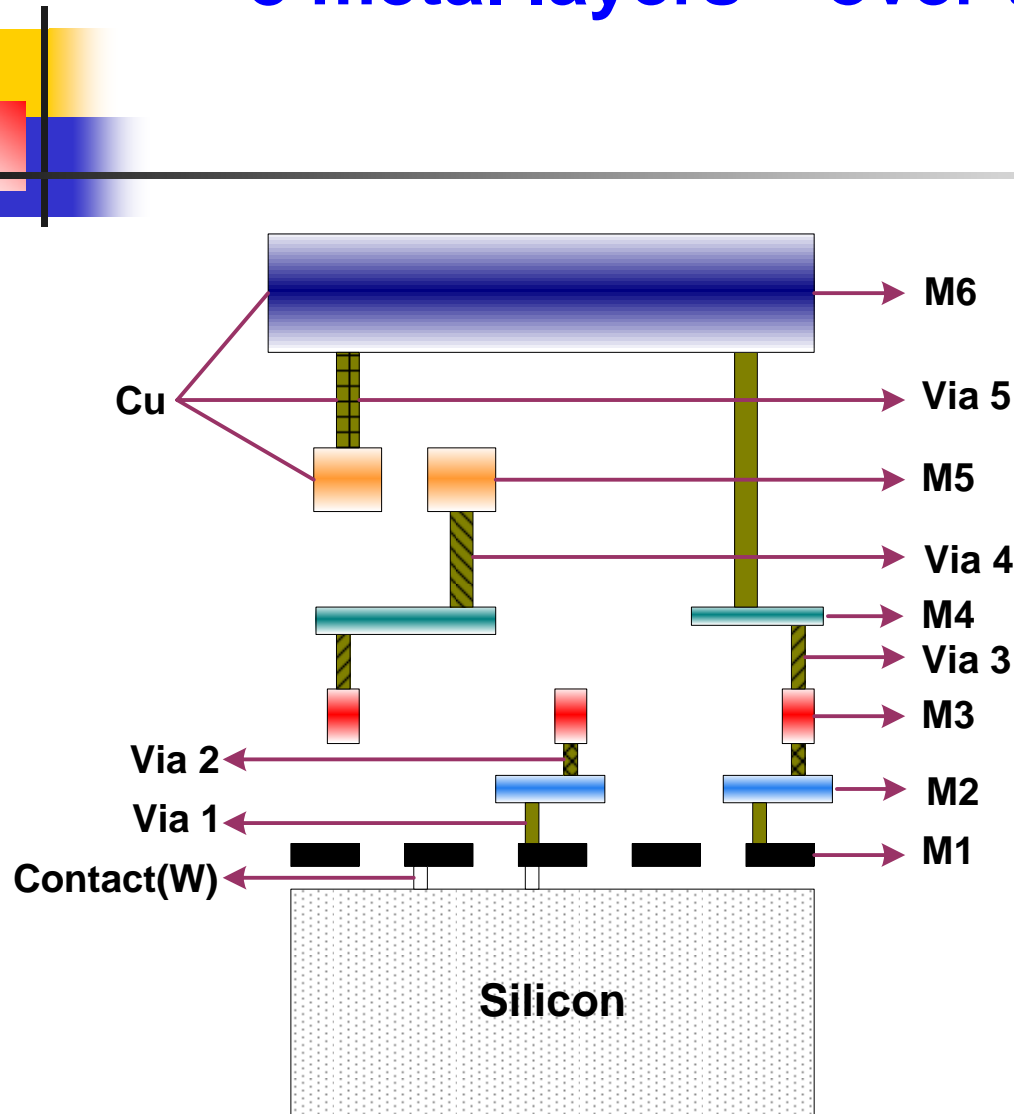
# Top View of Wafer with Chips



A single integrated circuit, also known as a **die, chip, and microchip**

# Snapshot- Profile of IC

## 8 metal layers – over the past 25 years



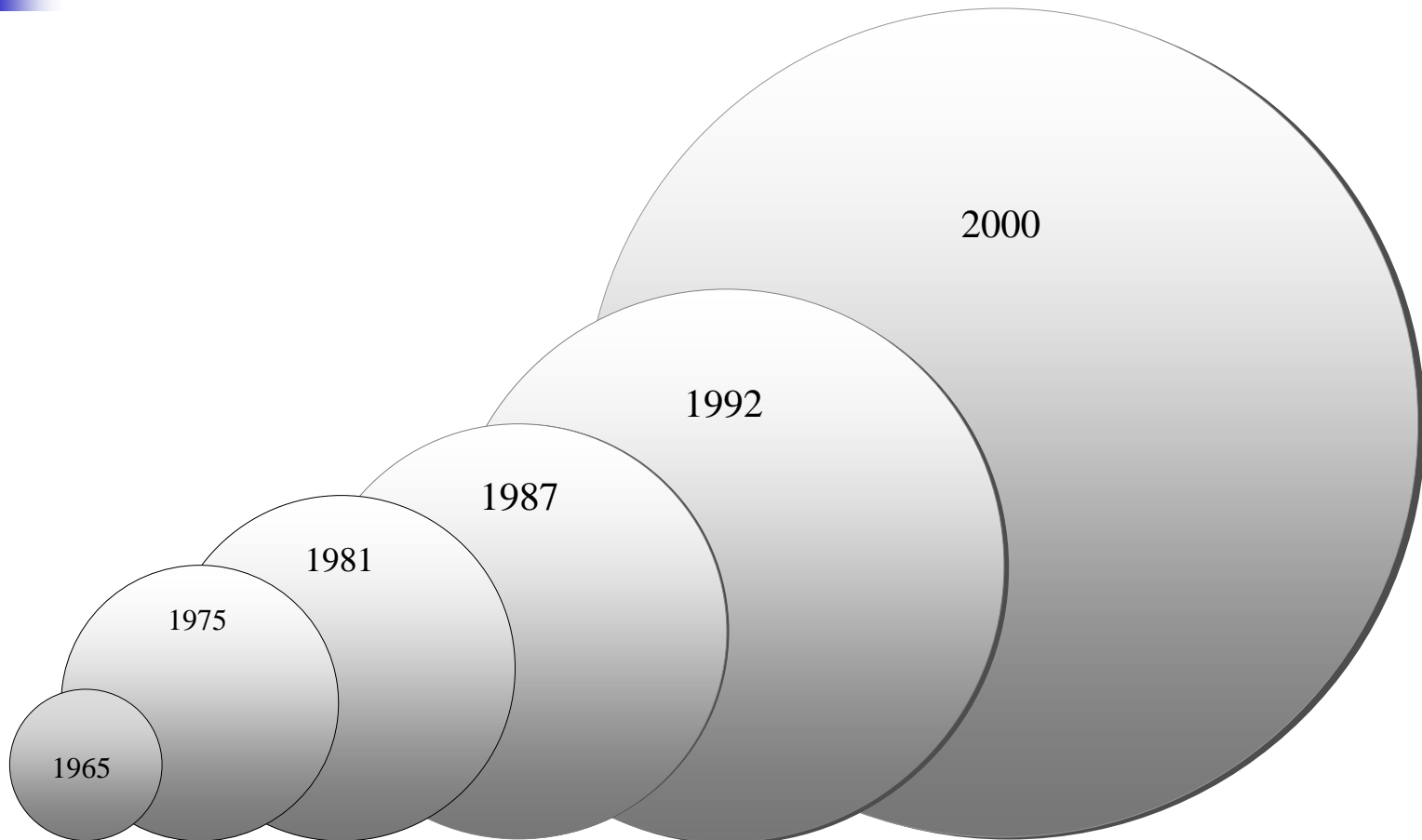


# IC Fabrication

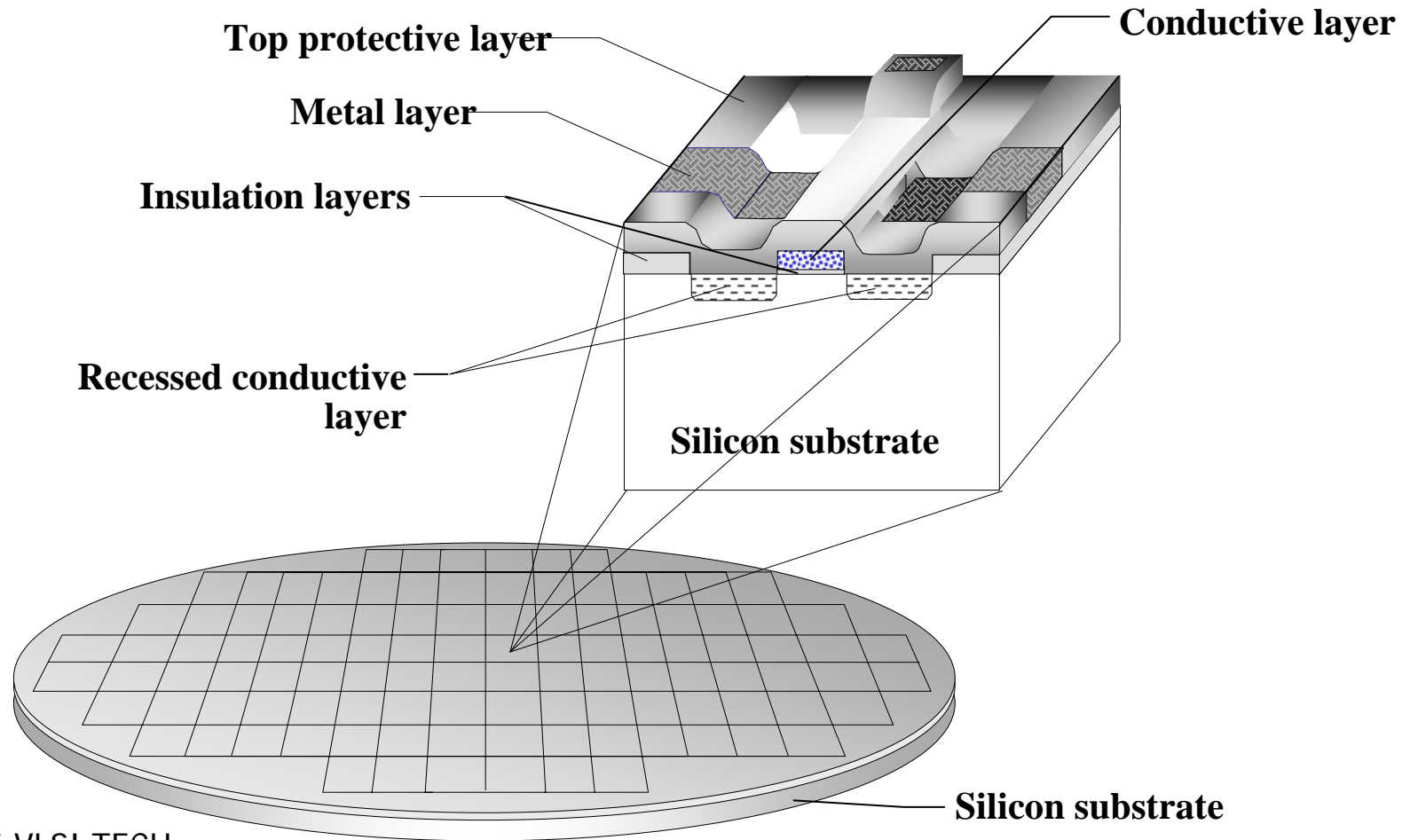
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- **Silicon**
  - **Wafer**
  - **Wafer Sizes**
  - **Devices and Layers**
- **Wafer Fab**
- **Stages of IC Fabrication**
  - **Wafer preparation**
  - **Wafer fabrication**
  - **Wafer test/sort**
  - **Assembly and packaging**
  - **Final test**

# Evolution of Wafer Size

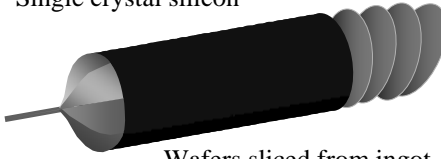
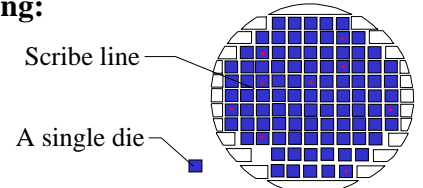
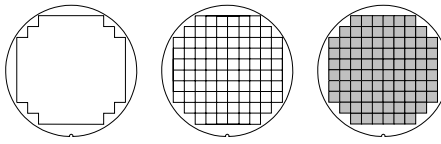
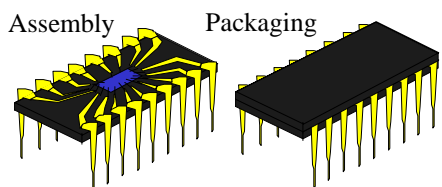
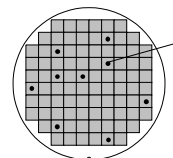
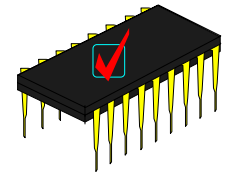


# Devices and Layers from a Silicon Chip

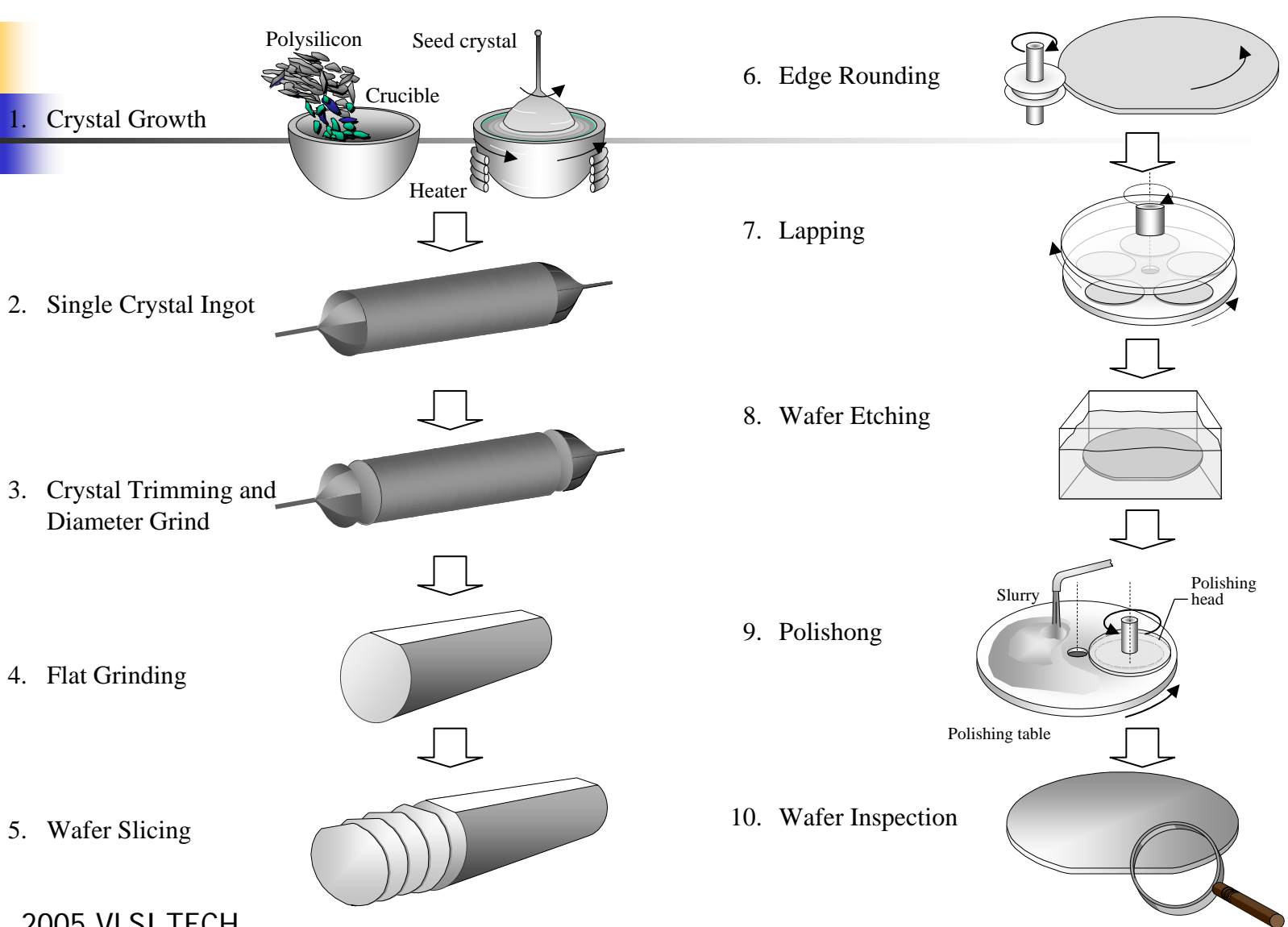




# Stages of IC Fabrication

<p>1. <b>Wafer Preparation</b> includes crystal growing, rounding, slicing and polishing.</p>	<p>Single crystal silicon</p>  <p>Wafers sliced from ingot</p>	<p>4. <b>Assembly and Packaging:</b></p> <p>The wafer is cut along scribe lines to separate each die.</p>  <p>Scribe line</p> <p>A single die</p>
<p>2. <b>Wafer Fabrication</b> includes cleaning, layering, patterning, etching and doping.</p>		<p>Metal connections are made and the chip is encapsulated.</p>  <p>Assembly</p> <p>Packaging</p>
<p>3. <b>Test/Sort</b> includes probing, testing and sorting of each die on the wafer.</p>	 <p>Defective die</p>	<p>5. <b>Final Test</b> ensures IC passes electrical and environmental testing.</p> 

# Preparation of Silicon Wafers

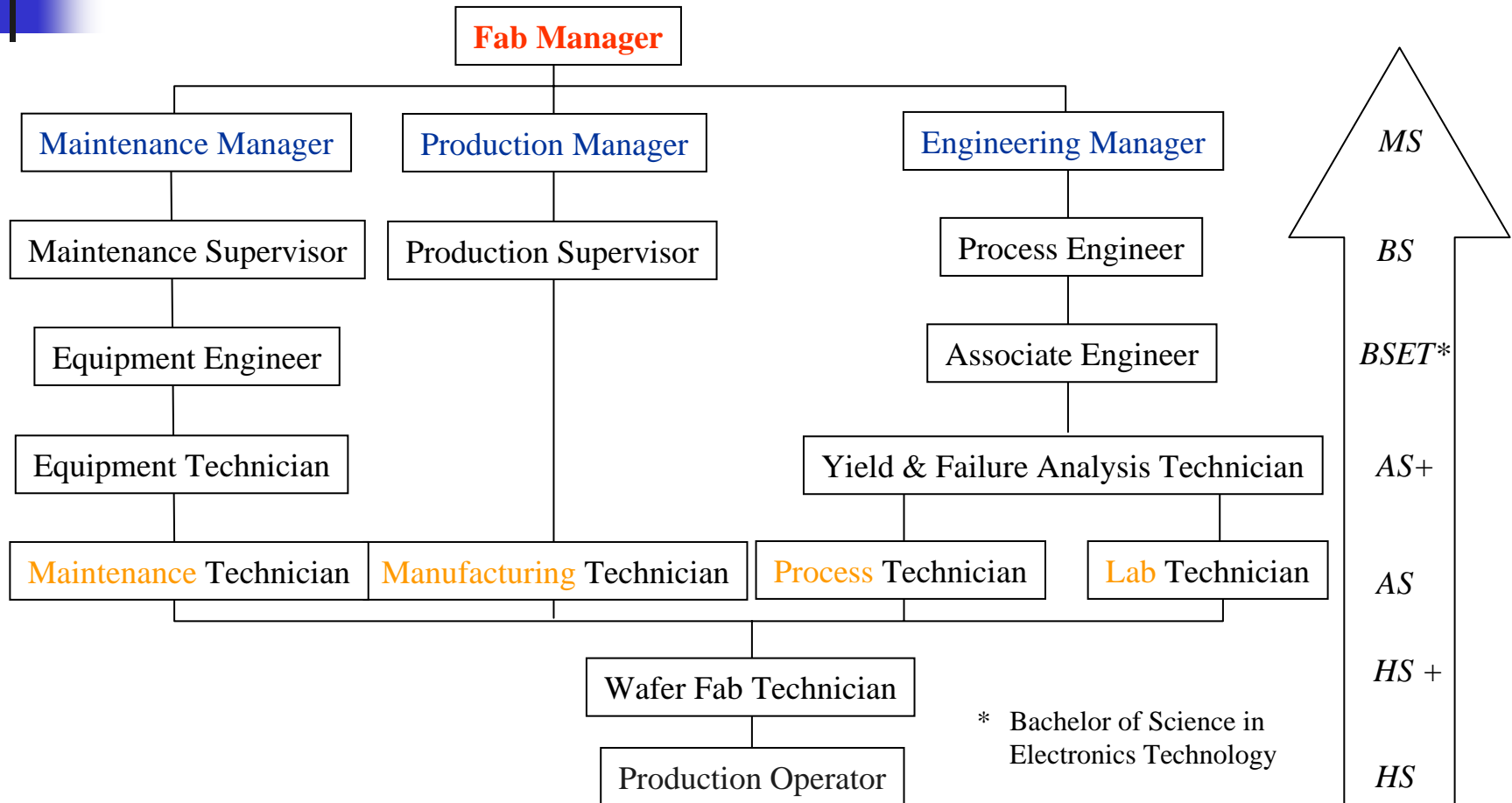


# Wafer Fab



2005 VLSI TECH. Photo courtesy of Advanced Micro Devices-Dresden, © S. Doering  
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# Career Paths in the Semiconductor Industry



# Circuit Integration of Semiconductors - Integration Eras

Circuit Integration	Semiconductor Industry Time Period	Number of Components per Chip
No integration (discrete components)	Prior to 1960	1
Small scale integration (SSI)	Early 1960s	2 to 50
Medium scale integration (MSI)	1960s to Early 1970s	50 to 5,000
Large scale integration (LSI)	Early 1970s to Late 1970s	5,000 to 100,000
Very large scale integration (VLSI)	Late 1970s to Late 1980s	100,000 to 1,000,000
Ultra large scale integration (ULSI)	1990s to present	> 1,000,000

## Semiconductor Trends :

- Increase in Chip Performance

- Components per Chip ↑

- Power Consumption ↓

- Increase in Chip Reliability

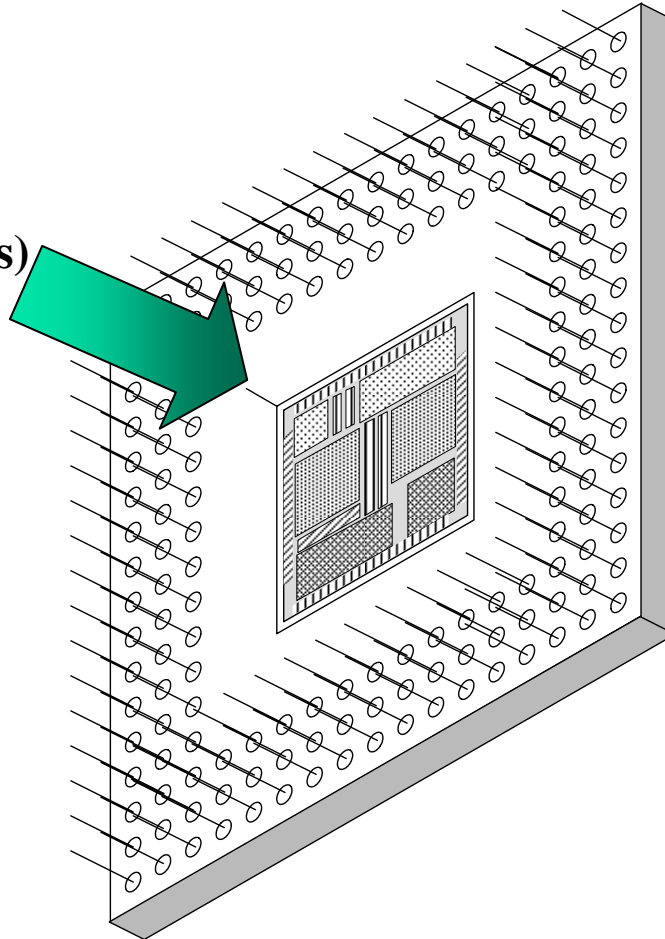
- Reduction in Chip Price

# Size Comparison of Early and Modern Semiconductors

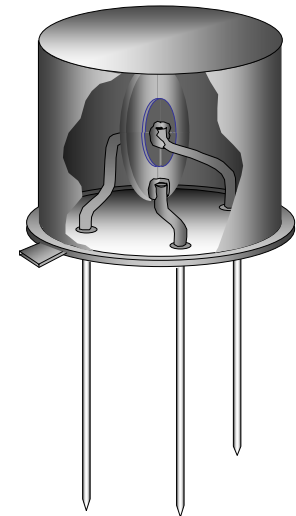
**1990s Microchip**  
(5~25 million transistors)

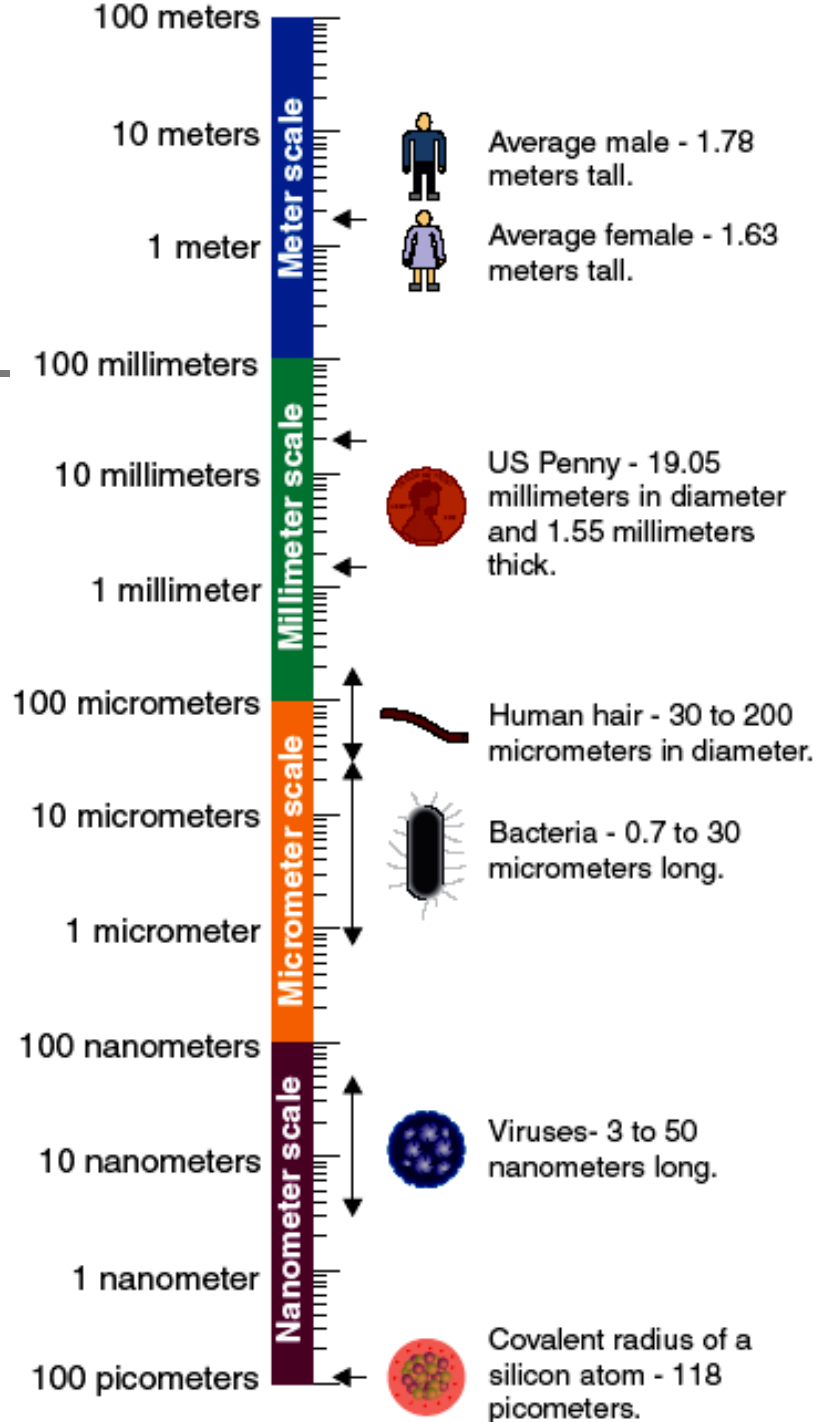
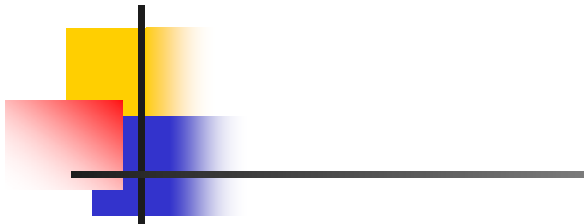


**U.S. coin, 10 cents**



**1960s Transistor**

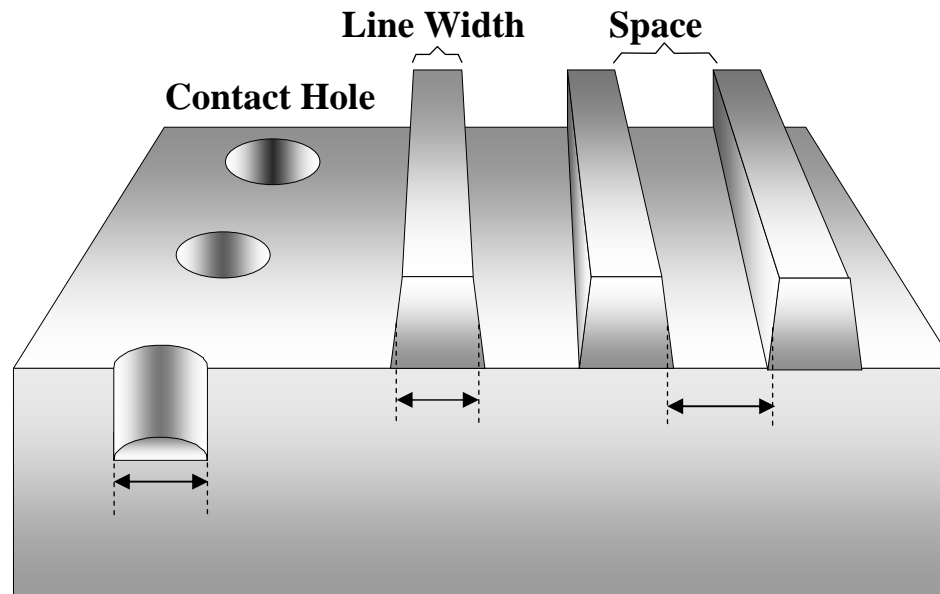




# Past and Future Technology Nodes for Device Critical Dimension (CD)

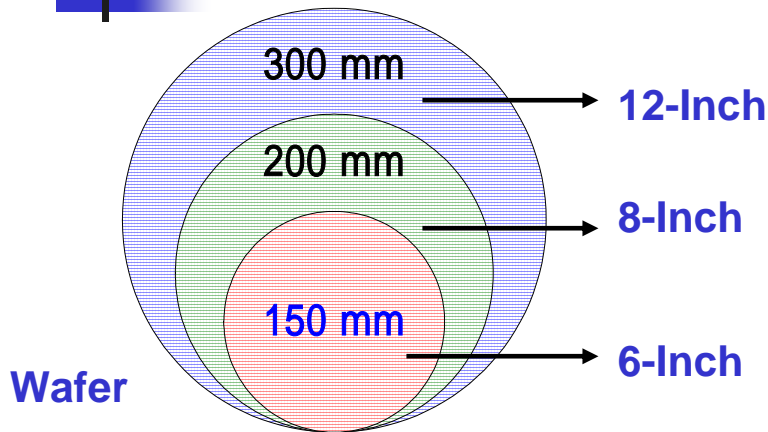
	1988	1992	1995	1997	1999	2001	2002	2005
CD ( $\mu\text{m}$ )	1.0	0.5	0.35	0.25	0.18	0.15	0.13	0.10

## Common IC Features





# Feature Technology and Size

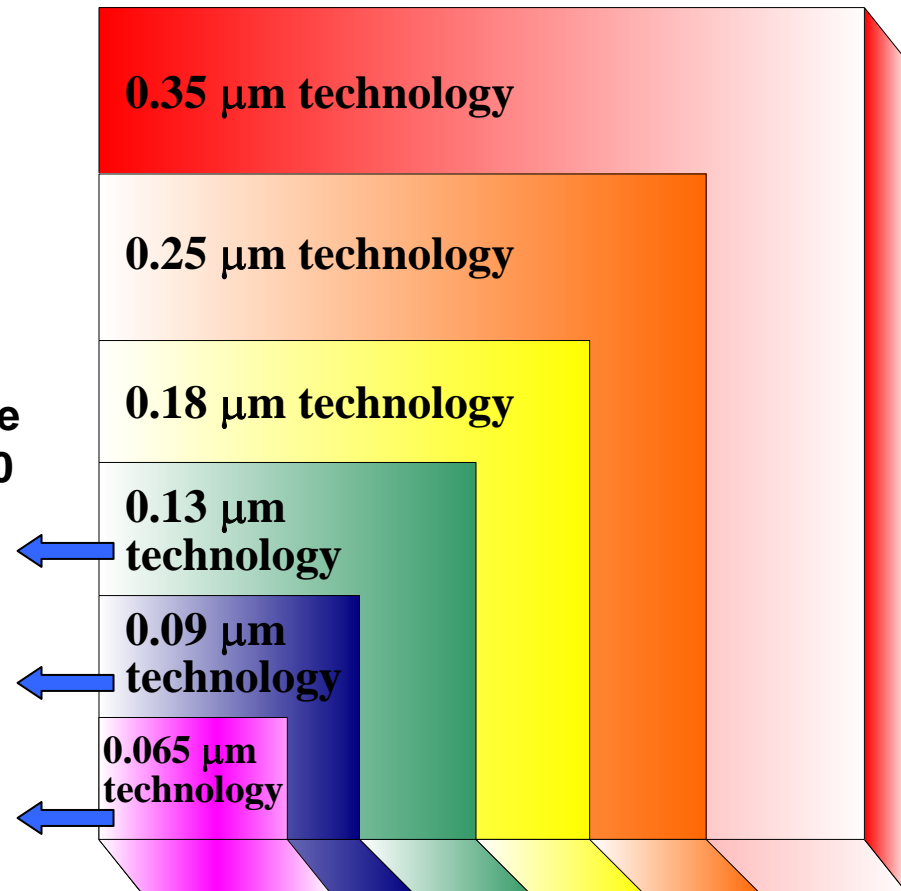


When compared to the **0.18-micron** process, the new **0.13-micron** process results in less than 60 percent the die size and nearly 70 percent improvement in performance

The **90-nm** process will be manufactured on 300mm wafers

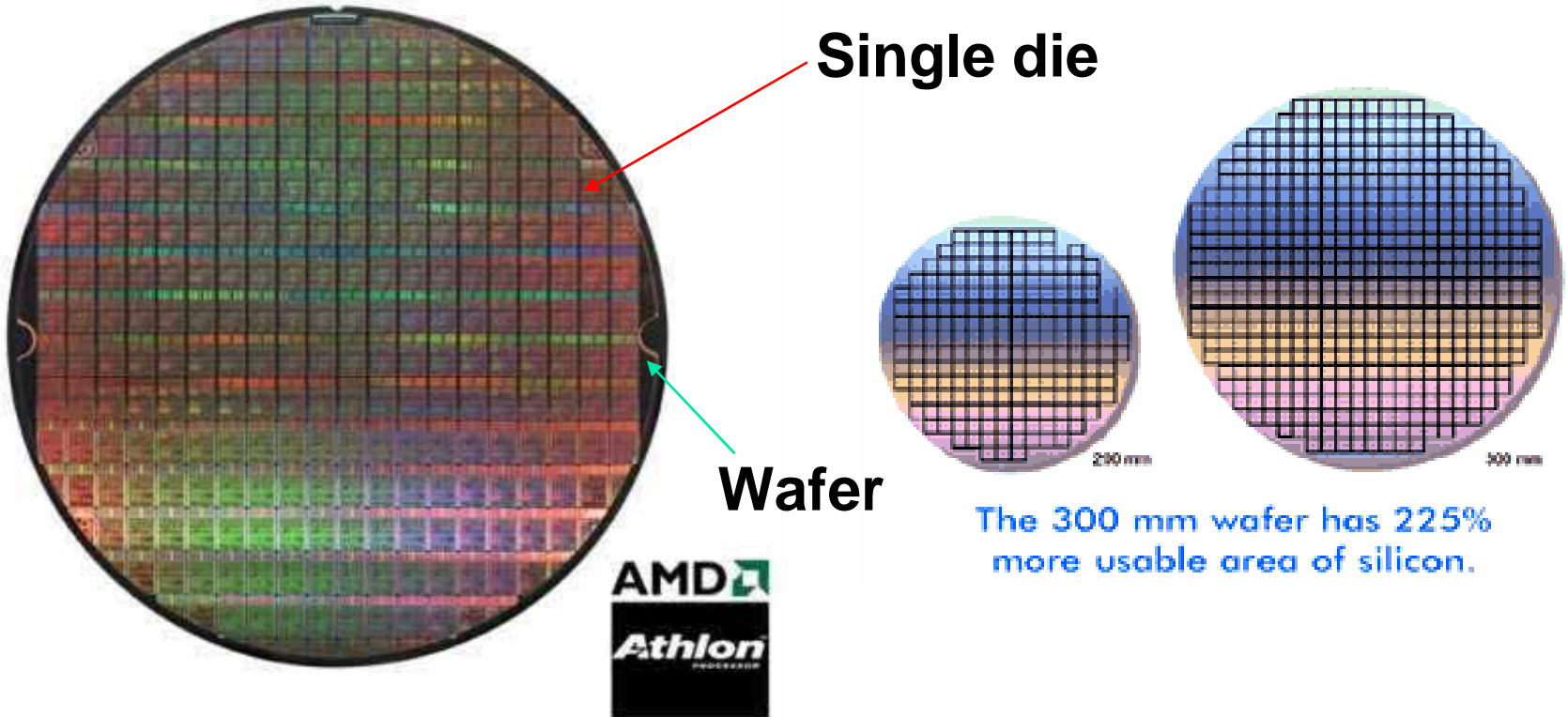
NEC devises low-k film for second-generation **65-nm** process

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# Die Size

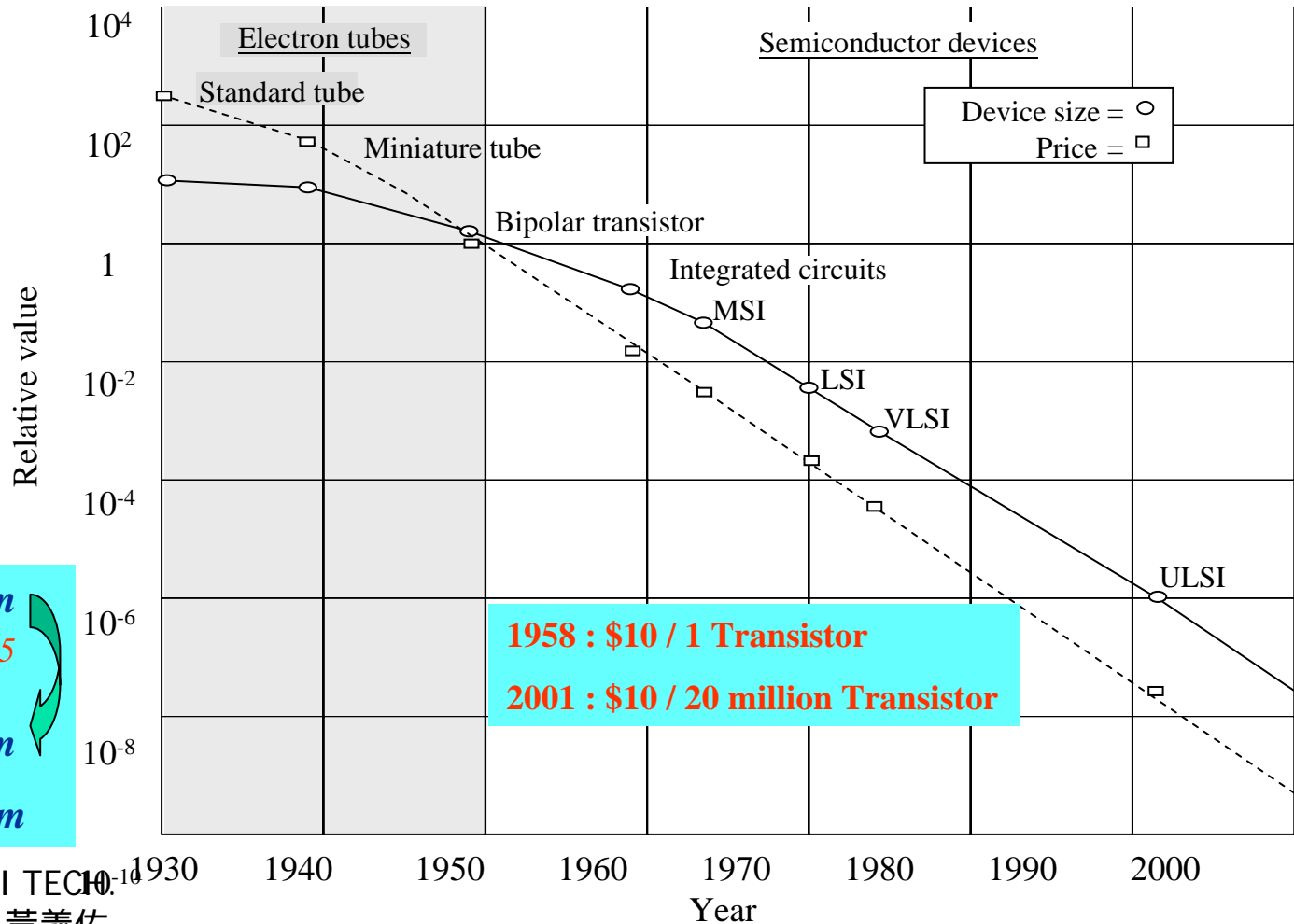
- Wafer photo



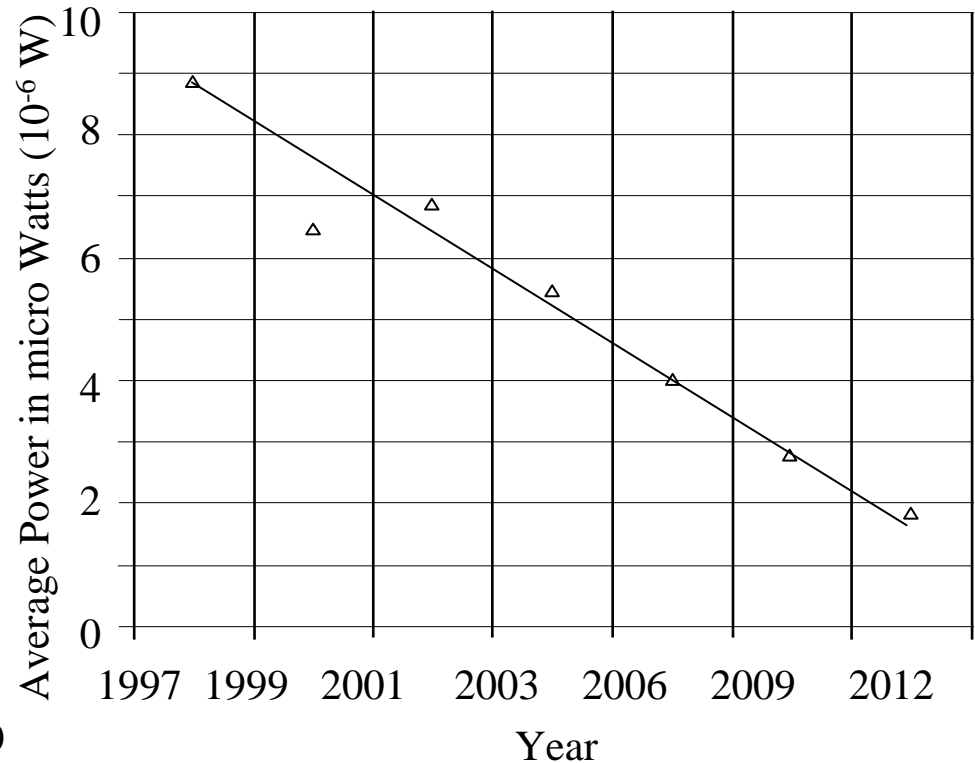
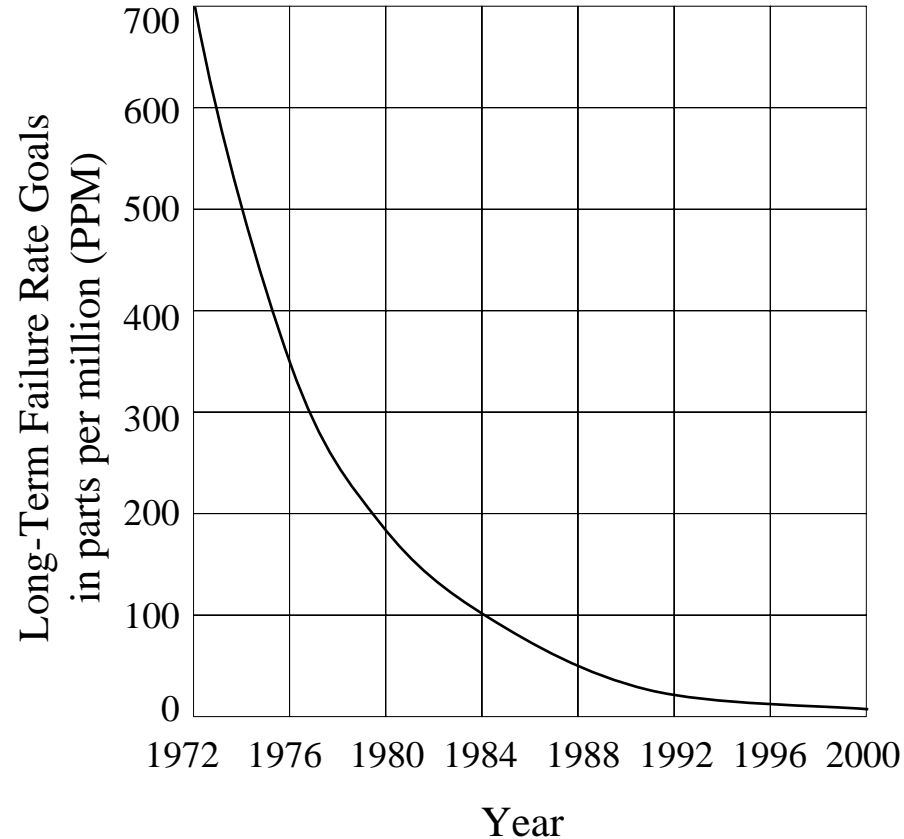
The 300 mm wafer has 225% more usable area of silicon.

From <http://www.amd.com>

# Price Decrease of Semiconductor Chips

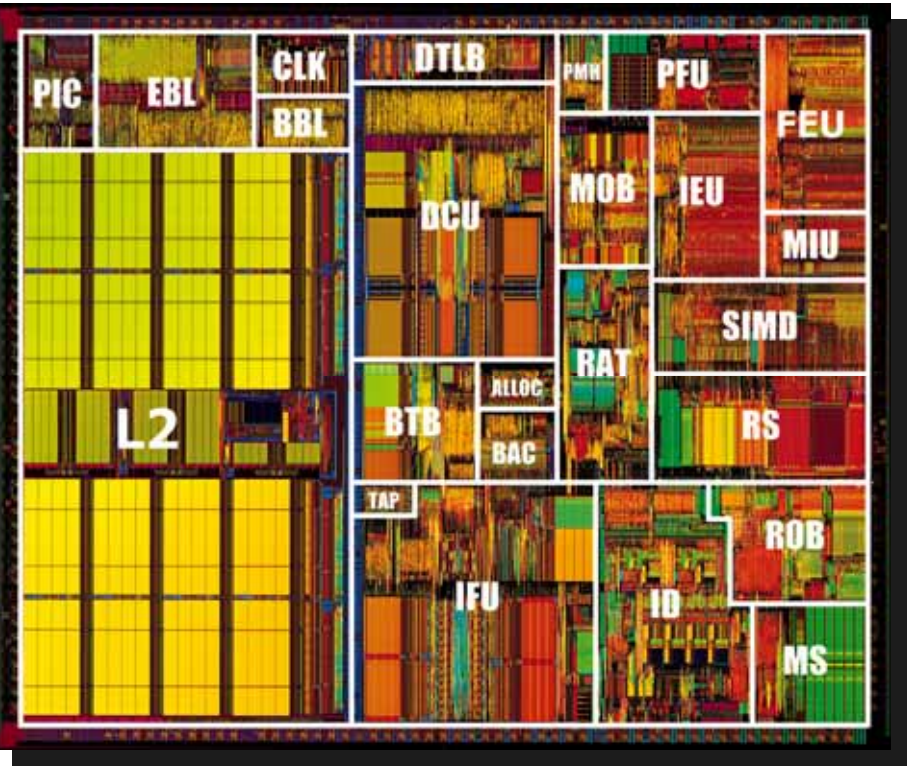
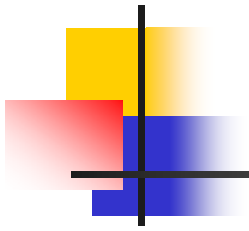


# Reliability Improvement of Chips & Reduction in Chip Power Consumption per IC



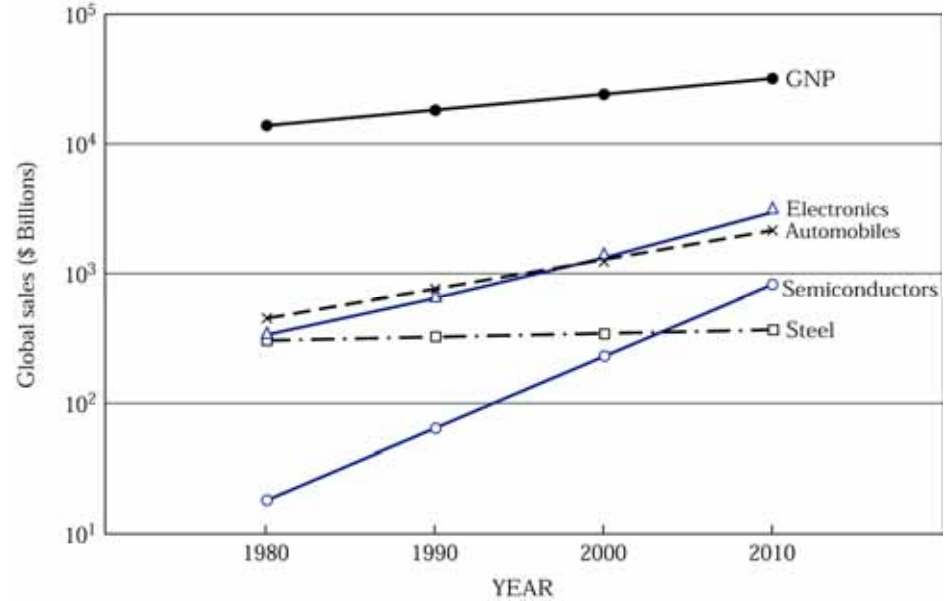
Redrawn from Semiconductor Industry Association (SIA)  
*National Technology Roadmap, 1997*

# ULSI Chip



Intel Corporation, Pentium III

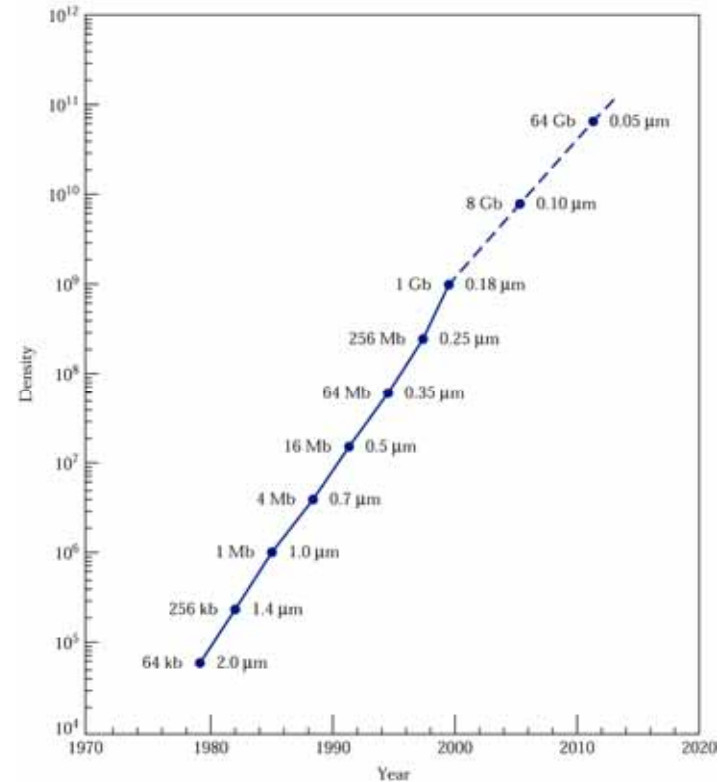
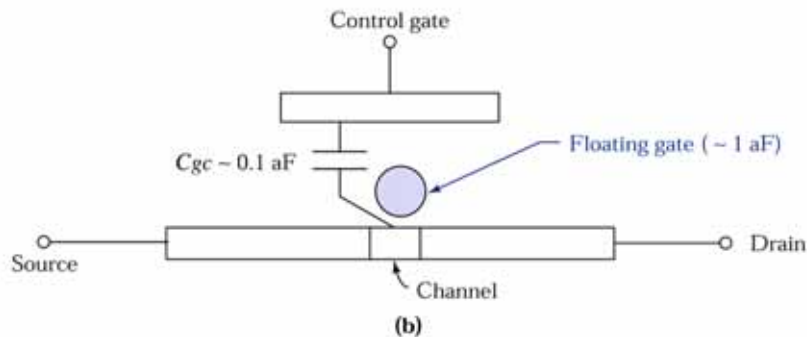
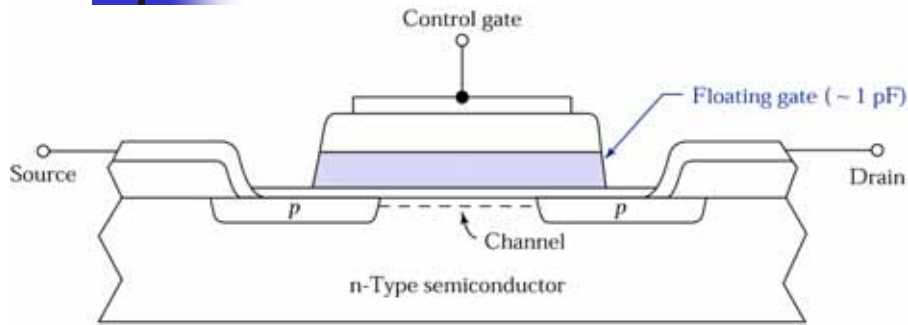
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► Gross world product (GWP) and sales volumes of the electronics, automobile, semiconductor, and steel industries from 1980 to 2000 and projected to 2010.

# IC Product #1:

## Semiconductor Memory Devices



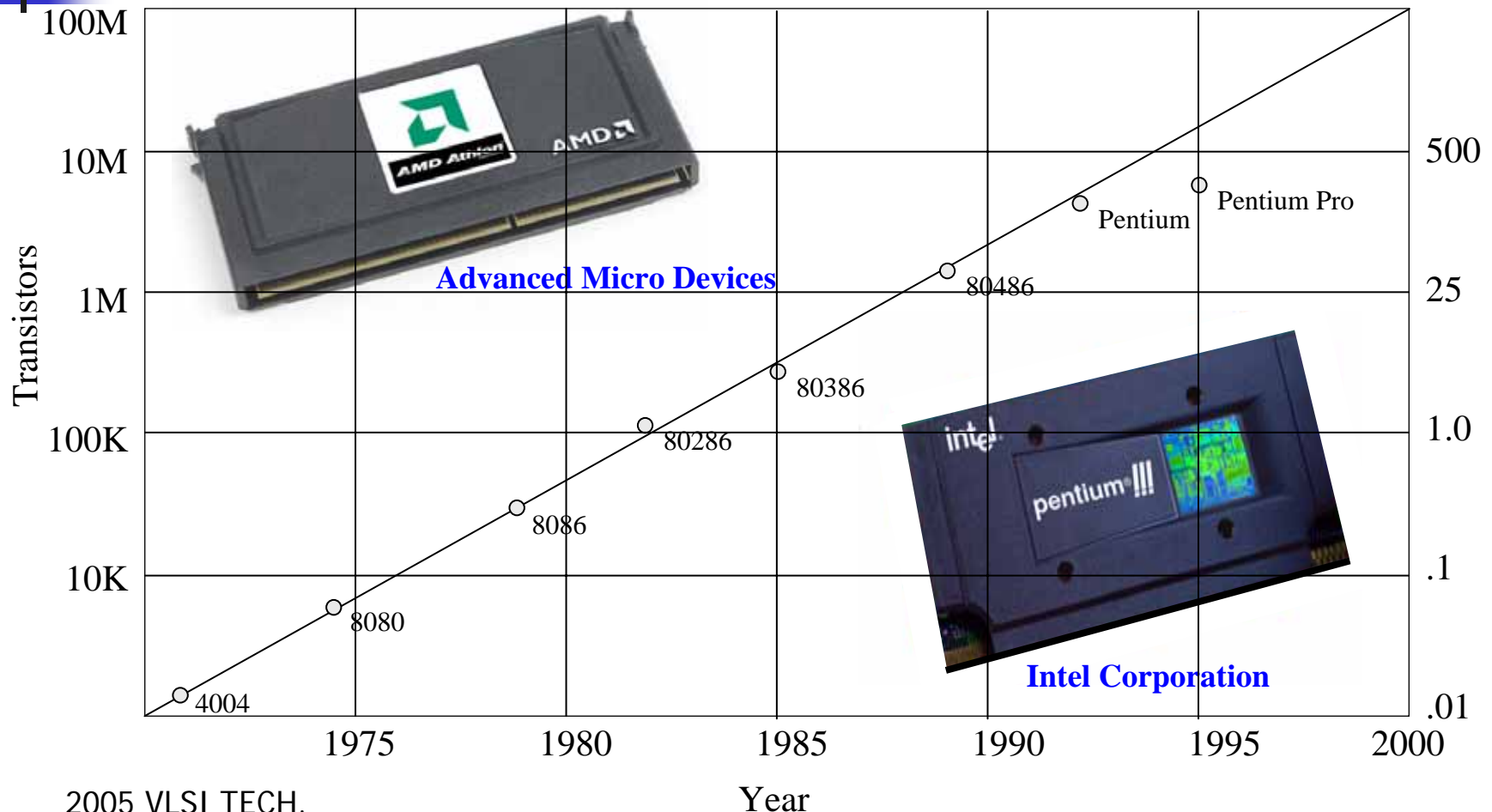
► (a) A schematic diagram of the first nonvolatile semiconductor memory (NVSM) with a floating gate. (b) A limiting case of the floating-gate NVSM—the single-electron memory cell.

► Exponential increase of dynamic random access memory (DRAM) density versus year based on the Semiconductor Industry Association (SIA) roadmap.

# IC Product #2 : Microprocessor Chips

## Moore's Law for Microprocessors

The number of transistors on a chip double every (12) 18 months.





# Moore's Law

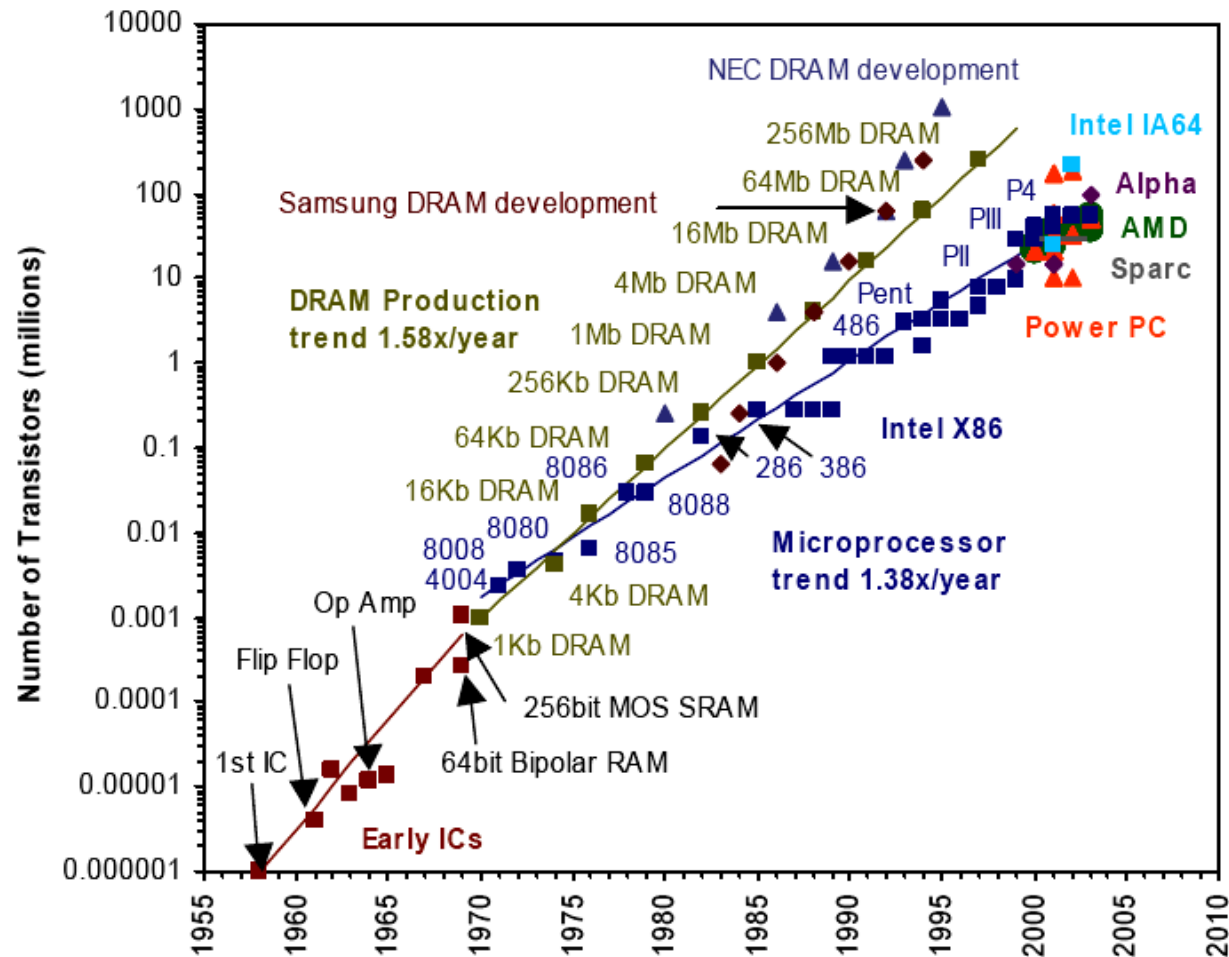
- Intel co-founder **Gordon Moore** notices in 1964
  - Number of transistors doubled every 12 months
  - Slowed down in the 1980s to every 18 months
    - Amazingly still correct likely to keep until 2010



Gordon Moore  
Intel Co-Founder and Chairmain  
Emeritus

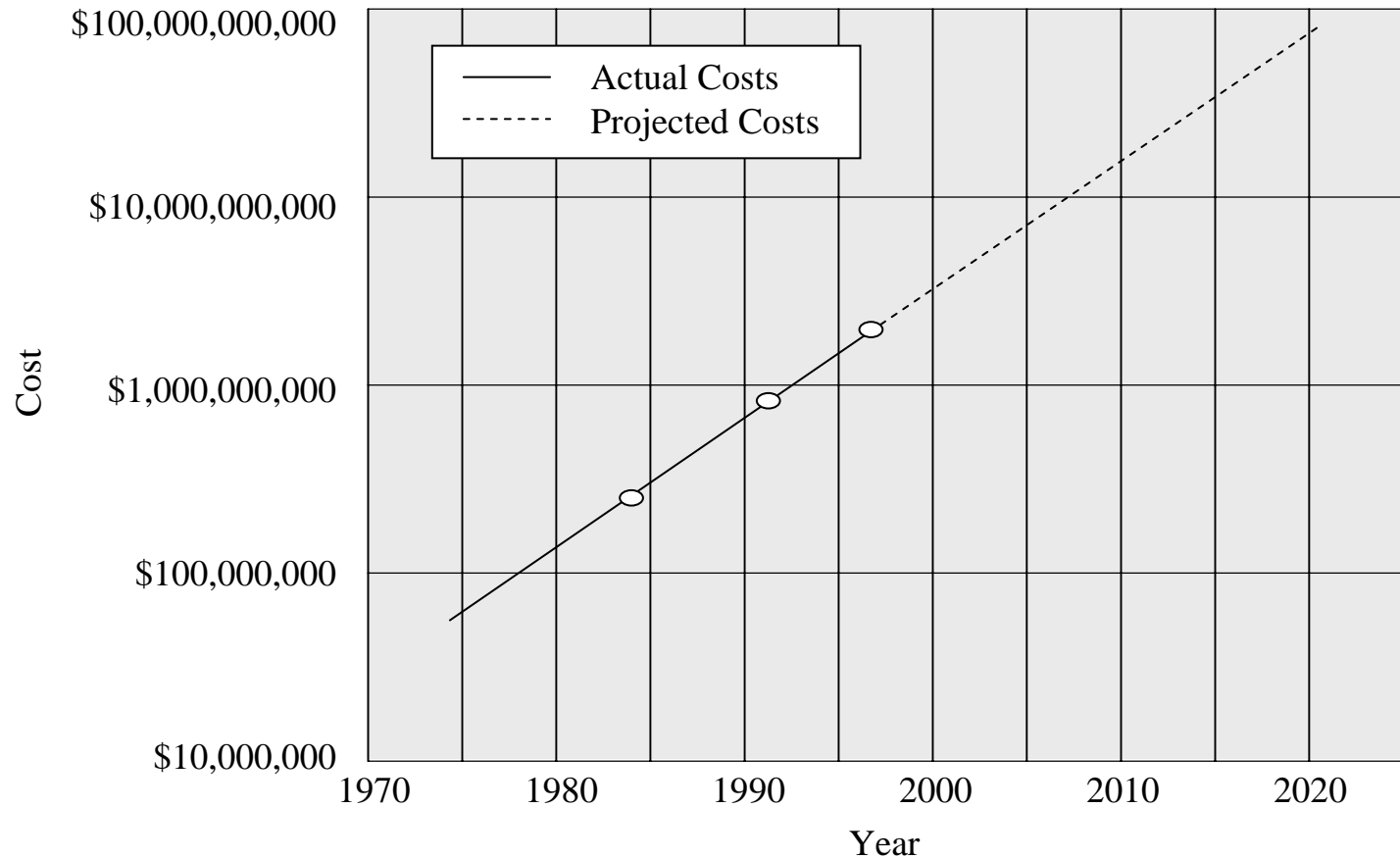
With Moore's Law, IC products can reach low costs, improve performance, and increase the functions.

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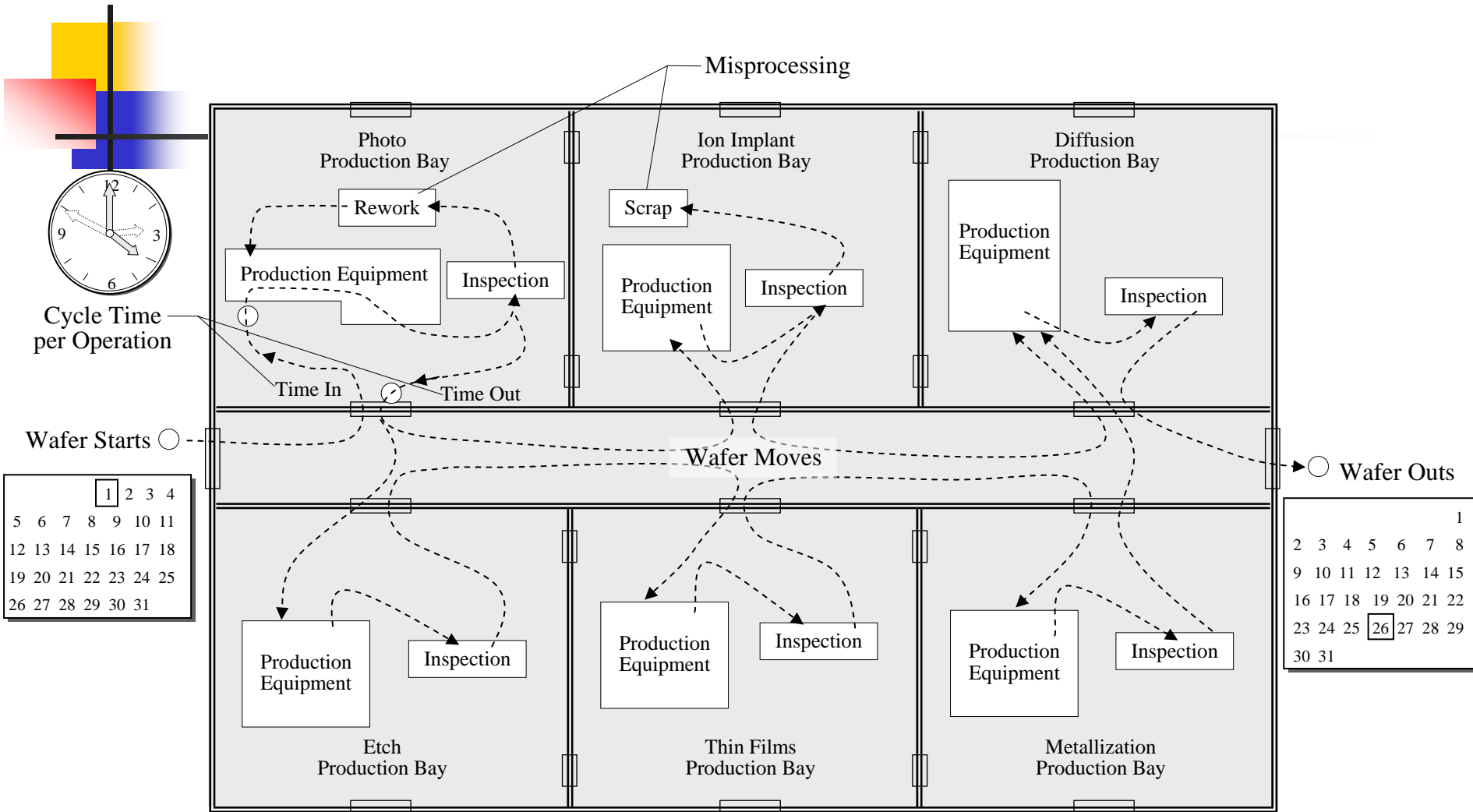




# Start-Up Cost of Wafer Fabs



# Productivity Measurements in a Wafer Fab



$$\text{Production Cycle Time} = (\text{Date and Time of Wafer Start}) - (\text{Date and Time of Wafer Out})$$

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$$\text{Wafer Outs} = \text{Wafer Starts} - \text{Wafers Scrapped}$$

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$$\text{Operator Efficiency} = \text{Theoretical Cycle Time} / \text{Actual Cycle Time}$$

# Equipment Technician in a Wafer Fab



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Photograph courtesy of Advanced Micro Devices

# Technician in Wafer Fab

